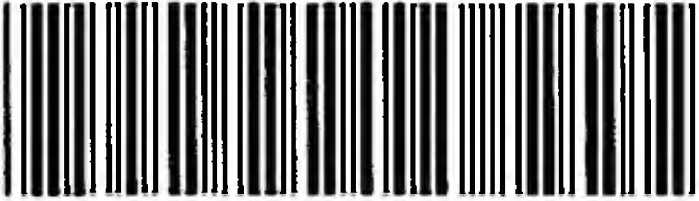


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/709,370	CHEN ET AL.	
	Examiner	Art Unit	
	David Nhu	2818	

SEARCHED			
Class	Subclass	Date	Examiner
438	266	4/2/2005	DN
↓	263, 264	↓	↓
	257, 258		
	197, 259		
	201, 202		
	289, 290		
	291, 292		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
438	266	4/2/2005	DN
✓	197	✓	✓
✓	257	✓	✓

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
SEARCHED IN EAST	4/2/2005	DN